



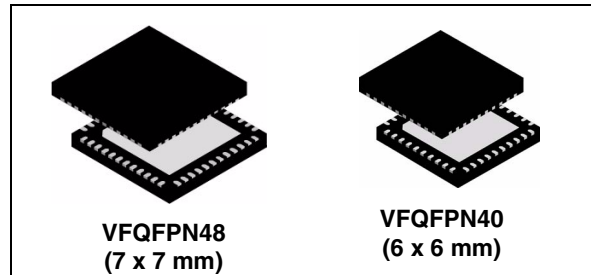
STM32W108HB STM32W108CB

High-performance, 802.15.4 wireless system-on-chip

Data brief

Features

- Complete System-on-Chip
 - 32-bit ARM® Cortex™-M3 processor
 - 2.4 GHz IEEE 802.15.4 transceiver & lower MAC
 - 128-Kbyte Flash, 8-Kbyte RAM memory
 - AES128 encryption accelerator
 - Flexible ADC, SPI/UART/TWI serial communications, and general-purpose timers
 - 24 highly configurable GPIOs with Schmitt trigger inputs
- Industry-leading ARM® Cortex™-M3 processor
 - Leading 32-bit processing performance
 - Highly efficient Thumb®-2 instruction set
 - Operation at 6, 12 or 24 MHz
 - Flexible nested vectored interrupt controller
- Low power consumption, advanced management
 - RX Current (w/ CPU): 27 mA
 - TX Current (w/ CPU, +3 dBm TX): 31 mA
 - Low deep sleep current, with retained RAM and GPIO: 400 nA/800 nA with/without sleep timer
 - Low-frequency internal RC oscillator for low-power sleep timing
 - High-frequency internal RC oscillator for fast (100 µs) processor start-up from sleep
- Exceptional RF performance
 - Normal mode link budget up to 102 dB; configurable up to 107 dB
 - -99 dBm normal RX sensitivity; configurable to -100 dBm (1% PER, 20 byte packet)
 - +3 dB normal mode output power; configurable up to +7 dBm
 - Robust WiFi and Bluetooth coexistence



- Innovative network and processor debug
 - Non-intrusive hardware packet trace
 - Serial wire/JTAG interface
 - Standard ARM debug capabilities: Flash patch & breakpoint; data watchpoint & trace; instrumentation trace macrocell
- Application flexibility
 - Single voltage operation: 2.1-3.6 V with internal 1.8 V and 1.25 V regulators
 - Optional 32.768 kHz crystal for higher timer accuracy
 - Low external component count with single 24 MHz crystal
 - Support for external power amplifier
 - Small 7x7 mm 48-pin QFN package or 6x6 mm 40-pin QFN package

Applications

- Smart energy
- Building automation and control
- Home automation and control
- Security and monitoring
- ZigBee® Pro wireless sensor networking
- RF4CE products and remote controls
- 6LoWPAN and custom protocols

Table 1. Device summary

Feature	STM32W108HB	STM32W108CB
Package	40-pin QFN	48-pin QFN

1 Description

The STM32W is a fully integrated System-on-Chip that integrates a 2.4 GHz, IEEE 802.15.4-compliant transceiver, 32-bit ARM® Cortex™-M3 microprocessor, Flash and RAM memory, and peripherals of use to designers of ZigBee-based systems.

The transceiver utilizes an efficient architecture that exceeds the dynamic range requirements imposed by the IEEE 802.15.4-2003 standard by over 15 dB. The integrated receive channel filtering allows for robust co-existence with other communication standards in the 2.4 GHz spectrum, such as IEEE 802.11 and Bluetooth. The integrated regulator, VCO, loop filter, and power amplifier keep the external component count low. An optional high performance radio mode (boost mode) is software-selectable to boost dynamic range.

The integrated 32-bit ARM® Cortex™-M3 microprocessor is highly optimized for high performance, low power consumption, and efficient memory utilization. Including an integrated MPU, it supports two different modes of operation: System mode and Application mode. The networking stack software runs in System mode with full access to all areas of the chip. Application code runs in Application mode with limited access to the STM32W resources; this allows for the scheduling of events by the application developer while preventing modification of restricted areas of memory and registers. This architecture results in increased stability and reliability of deployed solutions.

The STM32W has 128 Kbytes of embedded Flash memory and 8 Kbytes of integrated RAM for data and program storage. The STM32W HAL software employs an effective wear-leveling algorithm that optimizes the lifetime of the embedded Flash.

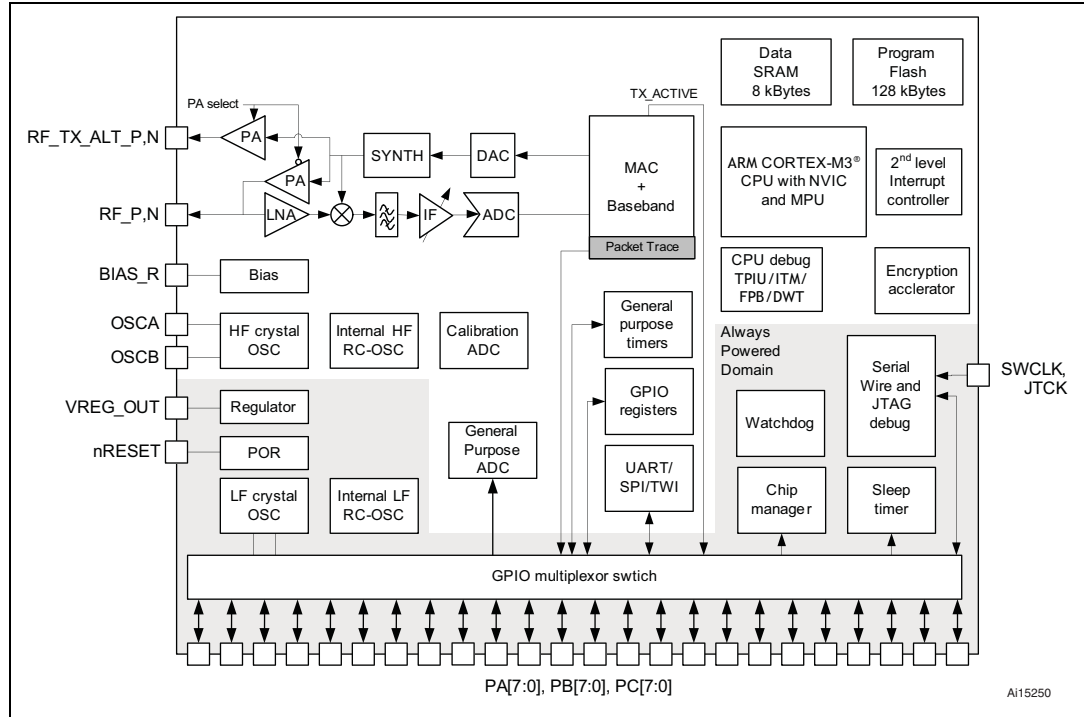
To maintain the strict timing requirements imposed by the ZigBee and IEEE 802.15.4-2003 standards, the STM32W integrates a number of MAC functions into the hardware. The MAC hardware handles automatic ACK transmission and reception, automatic backoff delay, and clear channel assessment for transmission, as well as automatic filtering of received packets. A packet trace interface is also integrated with the MAC, allowing complete, non-intrusive capture of all packets to and from the STM32W.

The STM32W offers a number of advanced power management features that enable long battery life. A high-frequency internal RC oscillator allows the processor core to begin code execution quickly upon waking. Various deep sleep modes are available with less than 1 μ A power consumption while retaining RAM contents. To support user-defined applications, on-chip peripherals include UART, SPI, TWI, ADC and general-purpose timers, as well as up to 24 GPIOs. Additionally, an integrated voltage regulator, power-on-reset circuit, and sleep timer are available.

1.1 Development tools

Finally, the STM32W utilizes standard Serial Wire and JTAG interfaces for powerful software debugging and programming of the ARM Cortex-M3 core. The STM32W integrates the standard ARM system debug components: Flash Patch and Breakpoint (FPB), Data Watchpoint and Trace (DWT), and Instrumentation Trace Macrocell (ITM).

Figure 1. STM32W block diagram



2 Electrical characteristics

2.1 Parameter conditions

Unless otherwise specified, all voltages are referenced to V_{SS} .

2.1.1 Minimum and maximum values

Unless otherwise specified the minimum and maximum values are guaranteed in the worst conditions of ambient temperature, supply voltage and frequencies by tests in production on 100% of the devices with an ambient temperature at $T_A = 25\text{ }^\circ\text{C}$ and $T_A = T_{A\text{max}}$ (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics are indicated in the table footnotes and are not tested in production. Based on characterization, the minimum and maximum values refer to sample tests and represent the mean value plus or minus three times the standard deviation (mean $\pm 3\sigma$).

2.1.2 Typical values

Unless otherwise specified, typical data are based on $T_A = 25\text{ }^\circ\text{C}$, $V_{DD} = 3.3\text{ V}$ (for the $2\text{ V} \leq V_{DD} \leq 3.6\text{ V}$ voltage range). They are given only as design guidelines and are not tested.

Typical ADC accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range, where 95% of the devices have an error less than or equal to the value indicated (mean $\pm 2\sigma$).

2.1.3 Typical curves

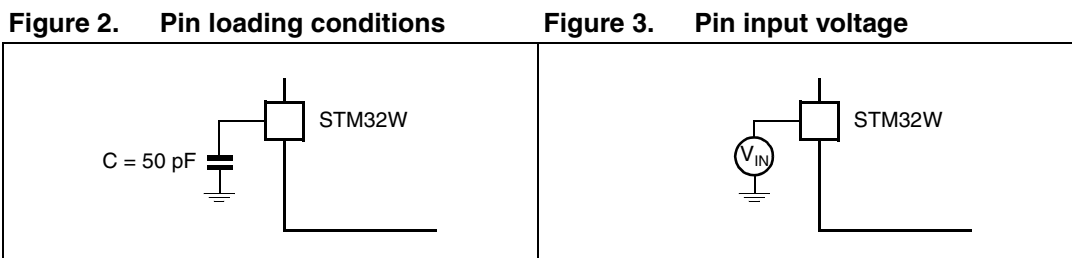
Unless otherwise specified, all typical curves are given only as design guidelines and are not tested.

2.1.4 Loading capacitor

The loading conditions used for pin parameter measurement are shown in [Figure 2](#).

2.1.5 Pin input voltage

The input voltage measurement on a pin of the device is described in [Figure 3](#).



2.2 Absolute maximum ratings

Stresses above the absolute maximum ratings listed in [Table 2: Voltage characteristics](#), [Table 3: Current characteristics](#), and [Table 4: Thermal characteristics](#) may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 2. Voltage characteristics

Ratings	Min.	Max.	Unit
Regulator input voltage (VDD_PADS)	-0.3	+3.6	V
Analog, Memory and Core voltage (VDD_24MHZ, VDD_VCO, VDD_RF, VDD_IF, VDD_PADSA, VDD_MEM, VDD_PRE, VDD_SYNTN, VDD_CORE)	-0.3	+2.0	V
Voltage on RF_P,N; RF_TX_ALT_P,N	-0.3	+3.6	V
RF Input Power (for max level for correct packet reception see Table 11: Receive characteristics) RX signal into a lossless balun		+15	dBm
Voltage on any GPIO (PA[7:0], PB[7:0], PC[7:0]), SWCLK, nRESET, VREG_OUT	-0.3	VDD_PADS +0.3	V
Voltage on BIAS_R, OSCA, OSCB	-0.3	VDD_PADSA +0.3	V

Table 3. Current characteristics

Symbol	Ratings	Max.	Unit
I_{VDD}	Total current into V_{DD}/V_{DDA} power lines (source)	150	mA
I_{VSS}	Total current out of V_{SS} ground lines (sink)	150	
I_{IO}	Output current sunk by any I/O and control pin	25	
	Output current source by any I/Os and control pin	- 25	
$I_{INJ(PIN)}$	Injected current on NRST pin	± 5	
	Injected current on HSE OSC_IN and LSE OSC_IN pins	± 5	
	Injected current on any other pin	± 5	
$\Sigma I_{INJ(PIN)}$	Total injected current (sum of all I/O and control pins)	± 25	

Table 4. Thermal characteristics

Symbol	Ratings	Value	Unit
T_{STG}	Storage temperature range	-40 to +140	°C
T_J	Maximum junction temperature	150	°C

2.3 Operating conditions

2.3.1 General operating conditions

Table 5. General operating conditions

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
–	Regulator input voltage (VDD_PADS)		2.1		3.6	V
–	Analog and memory input voltage (VDD_24MHZ, VDD_VCO, VDD_RF, VDD_IF, VDD_PADSA, VDD_MEM, VDD_PRE, VDD_SYNTN)		1.7	1.8	1.9	V
–	Core input voltage (VDD_CORE)		1.18	1.25	1.32	V
–	Operating temperature range		-40		+85	°C
f _{HCLK}	Internal AHB clock frequency		0		72	MHz
f _{PCLK1}	Internal APB1 clock frequency		0		36	
f _{PCLK2}	Internal APB2 clock frequency		0		72	
V _{DD}	Standard operating voltage		2		3.6	V
V _{DDA}	Analog operating voltage (ADC not used)	Must be the same potential as V _{DD}	2		3.6	V
	Analog operating voltage (ADC used)		2.4		3.6	
V _{BAT}	Backup operating voltage		1.8		3.6	V
T _A	Ambient temperature for 6 suffix version	Maximum power dissipation	-40		85	°C
		Low power dissipation	-40		105	
	Ambient temperature for 7 suffix version	Maximum power dissipation	-40		105	°C
		Low power dissipation	-40		125	
T _J	Junction temperature range	6 suffix version	-40		105	°C
		7 suffix version	-40		125	

2.3.2 Absolute maximum ratings (electrical sensitivity)

Based on three different tests (ESD, LU) using specific measurement methods, the device is stressed in order to determine its performance in terms of electrical sensitivity.

Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts × (n+1) supply pins). This test conforms to the JESD22-A114/C101 standard.

Table 6. ESD absolute maximum ratings

Symbol	Ratings	Conditions	Class	Maximum value ⁽¹⁾	Unit
V _{ESD(HBM)}	Electrostatic discharge voltage (human body model)	T _A = +25 °C conforming to JESD22-A114	2	±2000	V
V _{ESD(CDM)}	Electrostatic discharge voltage (charge device model) for non-RF pins	T _A = +25 °C conforming to JESD22-C101	II	±400	
	Electrostatic discharge voltage (charge device model) for RF pins			±225	
MSL	Moisture sensitivity level			MSL3	–

1. Based on characterization results, not tested in production.

Static latch-up

Two complementary static tests are required on six parts to assess the latch-up performance:

- A supply overvoltage is applied to each power supply pin
- A current injection is applied to each input, output and configurable I/O pin

These tests are compliant with EIA/JESD 78A IC latch-up standard.

Table 7. Electrical sensitivities

Symbol	Parameter	Conditions	Class
LU	Static latch-up class	T _A = +105 °C conforming to JESD78A	II level A

2.4 DC electrical characteristics

Table 8. DC electrical characteristics

Parameter	Conditions	Min.	Typ.	Max.	Unit
Regulator input voltage (VDD_PADS)		2.1		3.6	V
Power supply range (VDD_MEM)	Regulator output or external input	1.7	1.8	1.9	V
Power supply range (VDD_CORE)	Regulator output	1.18	1.25	1.32	V
Deep Sleep Current					
Quiescent current, internal RC oscillator disabled	-40°C, VDD_PADS = 3.6 V		0.4		µA
	+25°C, VDD_PADS = 3.6 V		0.4		µA
	+85°C, VDD_PADS = 3.6 V		0.6		µA

Table 8. DC electrical characteristics (continued)

Parameter	Conditions	Min.	Typ.	Max.	Unit
Quiescent current, including internal RC oscillator	-40°C, VDD_PADS=3.6 V		0.7		μA
	+25°C, VDD_PADS=3.6 V		0.8		μA
	+85°C, VDD_PADS=3.6 V		1.2		μA
Quiescent current, including 32.768 kHz oscillator	-40°C, VDD_PADS=3.6V		1.2		μA
	+25°C, VDD_PADS=3.6 V		1.3		μA
	+85°C, VDD_PADS=3.6 V		1.7		μA
Quiescent current, including internal RC oscillator and 32.768 kHz oscillator	-40°C, VDD_PADS=3.6V		1.4		μA
	+25°C, VDD_PADS=3.6V		1.5		μA
	+85°C, VDD_PADS=3.6 V		2.0		μA
Simulated deep sleep (debug mode) current	With no debugger activity		200		μA
Reset current					
Quiescent current, nRESET asserted	Typ at 25°C/3 V Max at 85°C/3.6 V		1.2		mA
Processor and peripheral currents					
ARM® Cortex-M3, RAM, and flash memory	25°C, 1.8 V memory and 1.25 V core ARM® Cortex-M3 running at 12 MHz from crystal oscillator Radio and all peripherals off		8.0		mA
ARM® Cortex-M3, RAM, and flash memory	25°C, 1.8 V memory and 1.25 V core ARM® Cortex-M3 running at 24 MHz from crystal oscillator Radio and all peripherals off		9.0		mA
ARM® Cortex-M3, RAM, and flash memory sleep current	25°C, 1.8 V memory and 1.25 V core ARM® Cortex-M3 clocked at 12 MHz from the crystal oscillator Radio and all peripherals off		4.0		mA
ARM® Cortex-M3, RAM, and flash memory sleep current	25°C, 1.8 V memory and 1.25 V core ARM® Cortex-M3 clocked at 6 MHz from the high frequency RC oscillator Radio and all peripherals off		2.0		mA
Serial controller current	For each controller at maximum data rate		0.2		mA
General purpose timer current	For each timer at maximum clock rate		0.1		mA

Table 8. DC electrical characteristics (continued)

Parameter	Conditions	Min.	Typ.	Max.	Unit
General purpose ADC current	At maximum sample rate, DMA enabled		1.1		mA
Rx current					
Radio receiver, MAC, and baseband	ARM® Cortex-M3 sleeping		20.0		mA
Total RX current (= I _{Radio receiver, MAC and baseband, CPU + I_{RAM, and Flash memory}})	VDD_PADS = 3.0 V, 25°C, ARM® Cortex-M3 running at 12 MHz		27.0		mA
	VDD_PADS = 3.0 V, 25°C, ARM® Cortex-M3 running at 24 MHz		28.0		mA
Boost mode total RX current (= I _{Radio receiver, MAC and baseband, CPU + I_{RAM, and Flash memory}})	VDD_PADS = 3.0 V, 25°C, ARM® Cortex-M3 running at 12 MHz		28.0		mA
	VDD_PADS = 3.0 V, 25°C, ARM® Cortex-M3 running at 24 MHz		29.0		mA
Tx current					
Radio transmitter, MAC, and baseband	25°C and 1.8 V core; max. power out (+3 dBm typical) ARM® Cortex-M3 sleeping		26.0		mA
Total Tx current (= I _{Radio transmitter, MAC and baseband, CPU + I_{RAM, and Flash memory}})	VDD_PADS = 3.0 V, 25°C; maximum power setting (+7dBm); ARM® Cortex-M3 running at 24 MHz		40.0		mA
	VDD_PADS = 3.0 V, 25°C; +3dBm power setting; ARM® Cortex-M3 running at 24 MHz		32.0		mA
	VDD_PADS = 3.0 V, 25°C; 0dBm power setting; ARM® Cortex-M3 running at 24 MHz		29.5		mA
	VDD_PADS = 3.0 V, 25°C; minimum power setting; ARM® Cortex-M3 running at 24 MHz		24.5		mA

Figure 4 shows the variation of current in transmit mode (with the ARM[®] Cortex-M3 running at 24 MHz).

Figure 4. Transmit power consumption

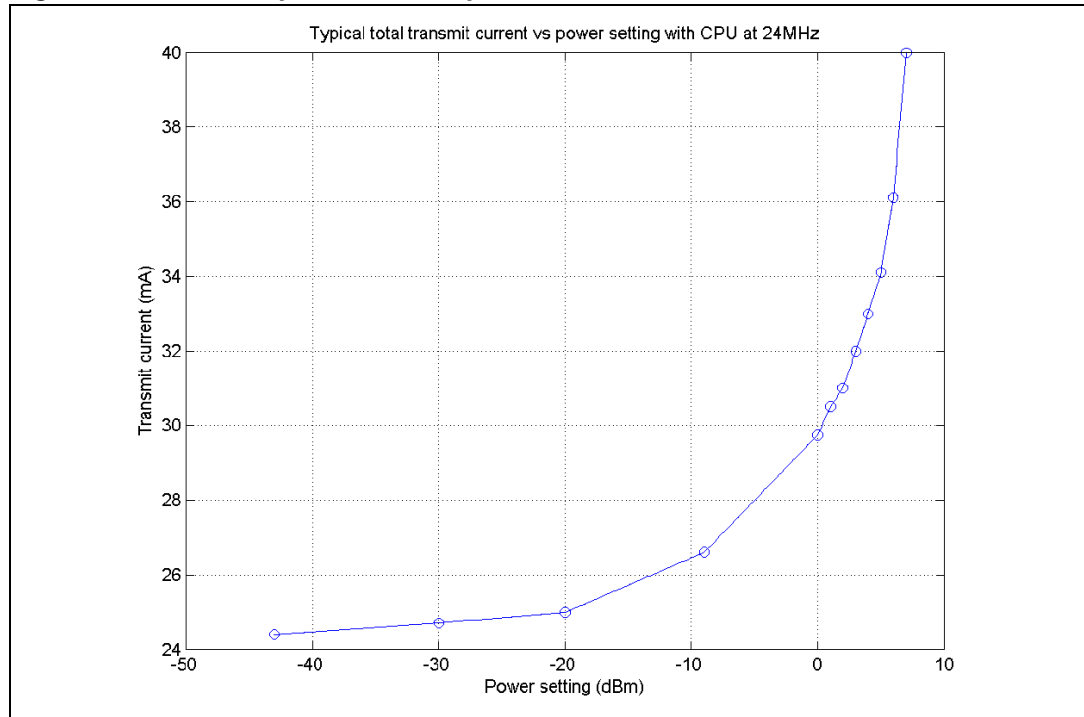
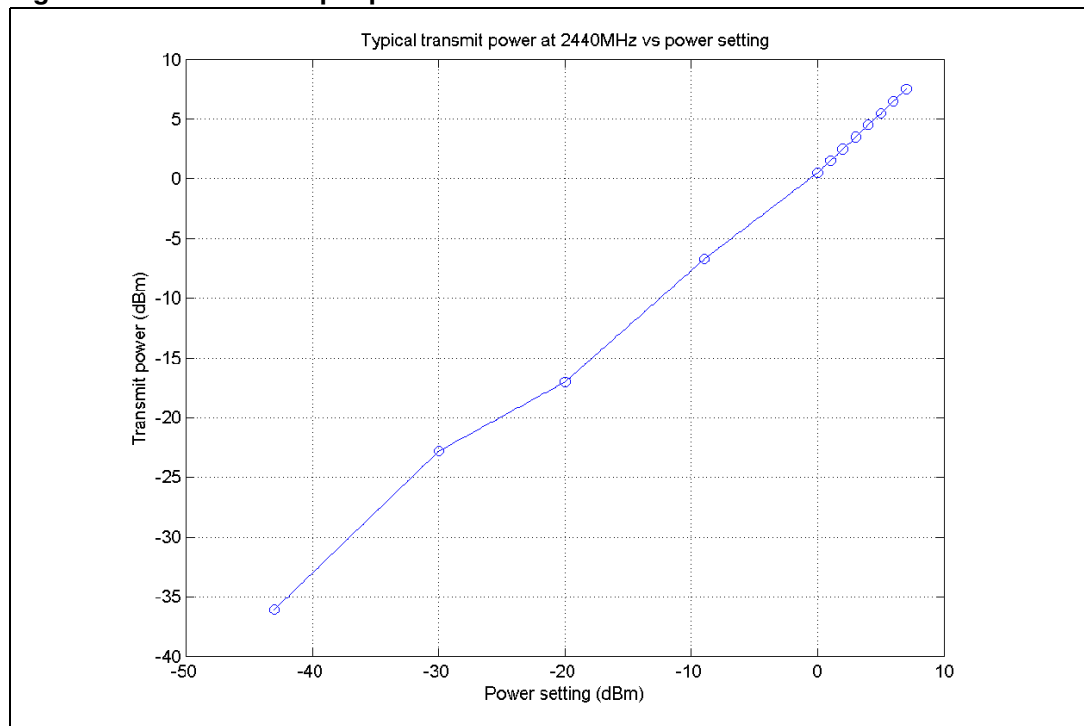


Figure 5 shows typical output power against power setting on the ST reference design.

Figure 5. Transmit output power



2.5 Digital I/O specifications

Table 9 lists the digital I/O specifications for the STM32W. The digital I/O power (named VDD_PADS) comes from three dedicated pins (Pins 23, 28 and 37). The voltage applied to these pins sets the I/O voltage.

Table 9. Digital I/O specifications

Parameter	Conditions	Min.	Typ.	Max.	Unit
Voltage supply (Regulator Input)	VDD_PADS	2.1		3.6	V
Low Schmitt switching threshold	V_{SWIL} Schmitt input threshold going from high to low	0.42 x VDD_PADS		0.50 x VDD_PADS	V
High Schmitt switching threshold	V_{SWIH} Schmitt input threshold going from low to high	0.62 x VDD_PADS		0.80 x VDD_PADS	V
Input current for logic 0	I_{IL}			-0.5	μ A
Input current for logic 1	I_{IH}			+0.5	μ A
Input pull-up resistor value	R_{IPU}	24	29	34	k Ω
Input pull-down resistor value	R_{IPD}	24	29	34	k Ω
Output voltage for logic 0	V_{OL} ($I_{OL} = 4$ mA for standard pads, 8 mA for high current pads)	0		0.18 x VDD_PADS	V
Output voltage for logic 1	V_{OH} ($I_{OH} = 4$ mA for standard pads, 8 mA for high current pads)	0.82 x VDD_PADS		VDD_PADS	V
Output source current (standard current pad)	I_{OHS}			4	mA
Output sink current (standard current pad)	I_{OLS}			4	mA
Output source current high current pad: PA6, PA7, PB6, PB7, PC0	I_{OHH}			8	mA
Output sink current high current pad: PA6, PA7, PB6, PB7, PC0	I_{OLH}			8	mA
Total output current (for I/O Pads)	$I_{OH} + I_{OL}$			40	mA
Input voltage threshold for OSC32A		0.2 x VDD_PADS		0.8 x VDD_PADS	V
Input voltage threshold for OSCA		0.2 x VDD_PADS A		0.8 x VDD_PADS A	V

2.6 Non-RF system electrical characteristics

Table 10 lists the non-RF system level characteristics for the STM32W.

Table 10. Non-RF system electrical characteristics

Parameter	Conditions	Min.	Typ.	Max.	Unit
System wake time from deep sleep	From wakeup event to first ARM® Cortex-M3 instruction running from 6MHz internal RC clock Includes supply ramp time and oscillator startup time	–	100	–	μs
Shutdown time going into deep sleep	From last ARM® Cortex-M3 instruction to deep sleep mode	–	5	–	μs

2.7 RF electrical characteristics

2.7.1 Receive

Table 11 lists the key parameters of the integrated IEEE 802.15.4 receiver on the STM32W.

Note: *Receive measurements were collected with ST's STM32W Ceramic Balun Reference Design (Version A0) at 2440 MHz. The Typical number indicates one standard deviation above the mean, measured at room temperature (25°C). The Min and Max numbers were measured over process corners at room temperature*

Table 11. Receive characteristics

Parameter	Conditions	Min.	Typ.	Max.	Unit
Frequency range		2400		2500	MHz
Sensitivity (boost mode)	1% PER, 20 byte packet defined by IEEE 802.15.4-2003		-100	-95	dBm
Sensitivity	1% PER, 20 byte packet defined by IEEE 802.15.4-2003		-99	-94	dBm
High-side adjacent channel rejection	IEEE 802.15.4 signal at -82 dBm		35		dB
Low-side adjacent channel rejection	IEEE 802.15.4 signal at -82 dBm		35		dB
2 nd high-side adjacent channel rejection	IEEE 802.15.4 signal at -82 dBm		43		dB
2 nd low-side adjacent channel rejection	IEEE 802.15.4 signal at -82 dBm		43		dB
Channel rejection for all other channels	IEEE 802.15.4 signal at -82 dBm		40		dB
802.11g rejection centered at +12 MHz or -13 MHz	IEEE 802.15.4 signal at -82 dBm		35		dB
Maximum input signal level for correct operation		0			dBm

Table 11. Receive characteristics (continued)

Parameter	Conditions	Min.	Typ.	Max.	Unit
Co-channel rejection	IEEE 802.15.4 signal at -82 dBm		-6		dBc
Relative frequency error (2x40 ppm required by IEEE 802.15.4)		-120		+120	ppm
Relative timing error (2x40 ppm required by IEEE 802.15.4)		-120		+120	ppm
Linear RSSI range	As defined by IEEE 802.15.4	40			dB
RSSI Range		-90		-30	dBm

2.7.2 Transmit

Table 12 lists the key parameters of the integrated IEEE 802.15.4 transmitter on the STM32W.

Note: *Transmit measurements were collected with ST's STM32W Ceramic Balun Reference Design (Version A0) at 2440 MHz. The Typical number indicates one standard deviation above the mean, measured at room temperature (25°C). The Min and Max numbers were measured over process corners at room temperature*

Table 12. Transmit characteristics

Parameter	Conditions	Min.	Typ.	Max.	Unit
Maximum output power (boost mode)	At highest power setting		7		dBm
Maximum output power	At highest power setting	0	3		dBm
Minimum output power	At lowest power setting		-32		dBm
Error vector magnitude	As defined by IEEE 802.15.4, which sets a 35% maximum		5	15	%
Carrier frequency error		-40		+40	ppm
Load impedance for optimum transmit power			200+j90 TBC		?
PSD mask relative	3.5 MHz away	-20			dB
PSD mask absolute	3.5 MHz away	-30			dBm

2.7.3 Synthesizer

Table 13 lists the key parameters of the integrated synthesizer on the STM32W.

Table 13. Synthesizer characteristics

Parameter	Conditions	Min.	Typ.	Max.	Unit
Frequency range		2400		2500	MHz
Frequency resolution			11.7		kHz
Lock time	From off, with correct VCO DAC setting			100	μs
Relock time	Channel change or RX/TX turnaround (IEEE 802.15.4 defines 192 μs turnaround time)			100	μs
Phase noise at 100 kHz offset			-71		dBc/Hz
Phase noise at 1 MHz offset			-91		dBc/Hz
Phase noise at 4 MHz offset			-103		dBc/Hz
Phase noise at 10 MHz offset			-111		dBc/Hz

3 Package characteristics

3.1 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

Figure 6. VFQFPN48 7x7mm package outline

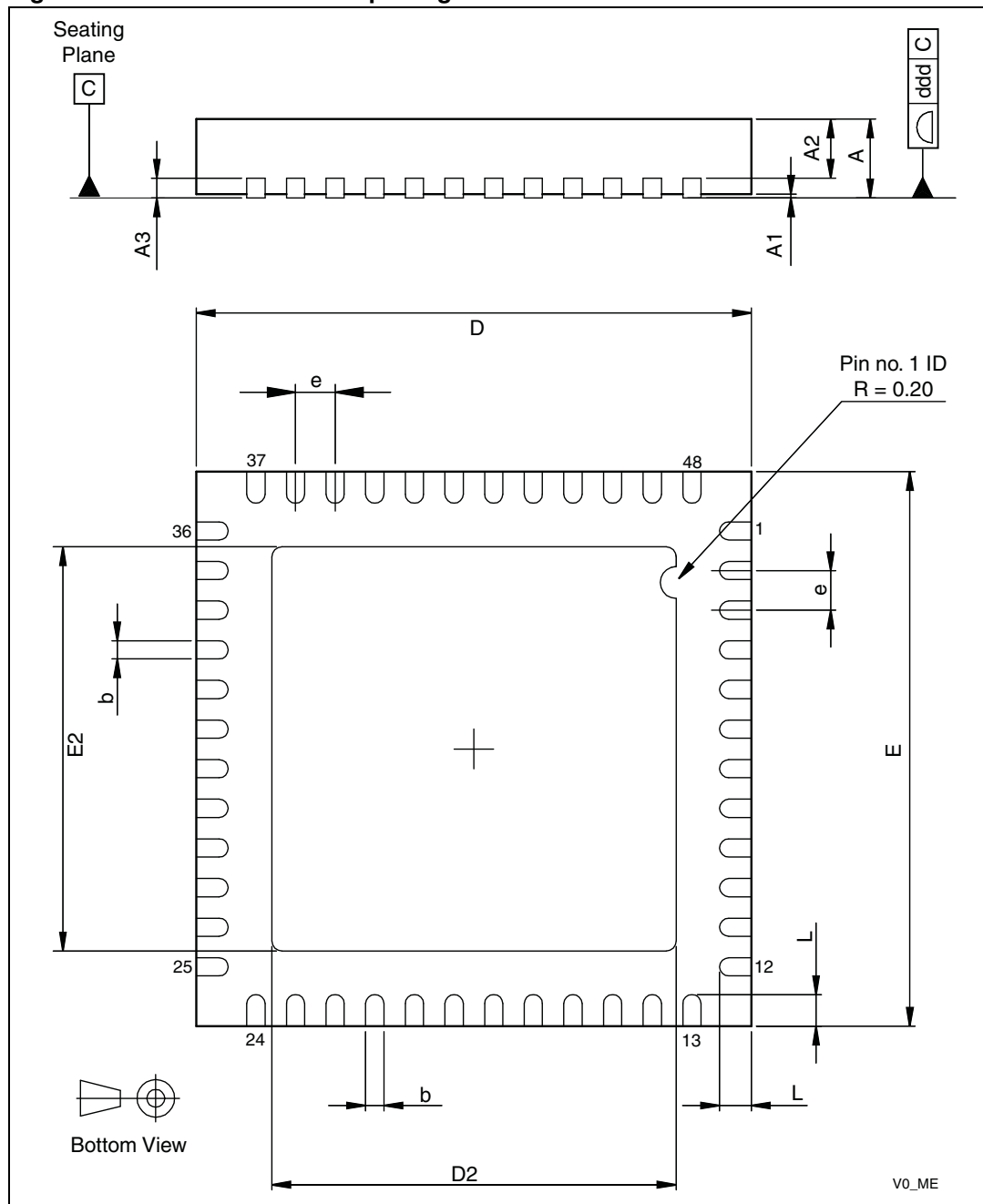


Table 14. VFQFPN48 7x7mm package mechanical data

Symbol	Millimeters			Inches ⁽¹⁾		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	0.800	0.900	1.000	0.0315	0.0354	0.0394
A1		0.020	0.050		0.0008	0.0020
A2		0.650	1.000		0.0256	0.0394
A3		0.250			0.0098	
b	0.180	0.230	0.300	0.0071	0.0091	0.0118
D	6.850	7.000	7.150	0.2697	0.2756	0.2815
D2	2.250	4.700	5.250	0.0886	0.1850	0.2067
E	6.850	7.000	7.150	0.2697	0.2756	0.2815
E2	2.250	4.700	5.250	0.0886	0.1850	0.2067
e	0.450	0.500	0.550	0.0177	0.0197	0.0217
L	0.300	0.400	0.500	0.0118	0.0157	0.0197
ddd			0.080			0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 7. QFN 40L 6x6mm pitch 0.5 package outline

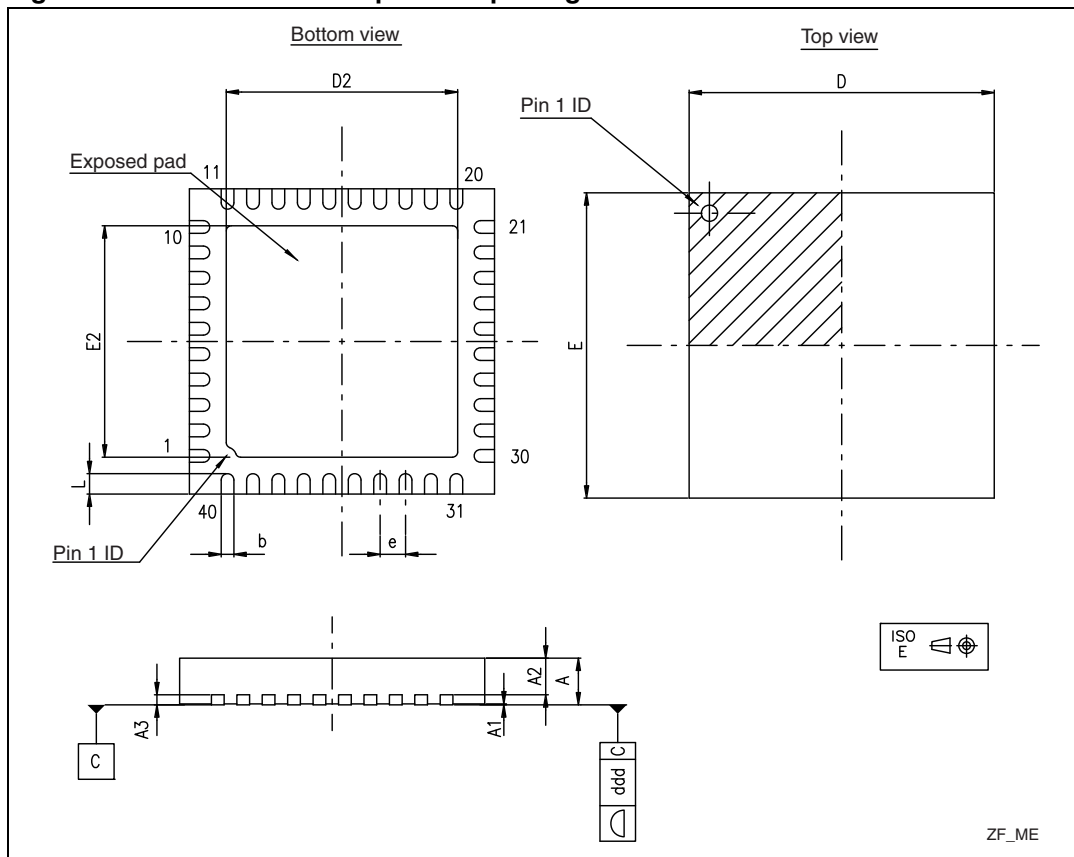
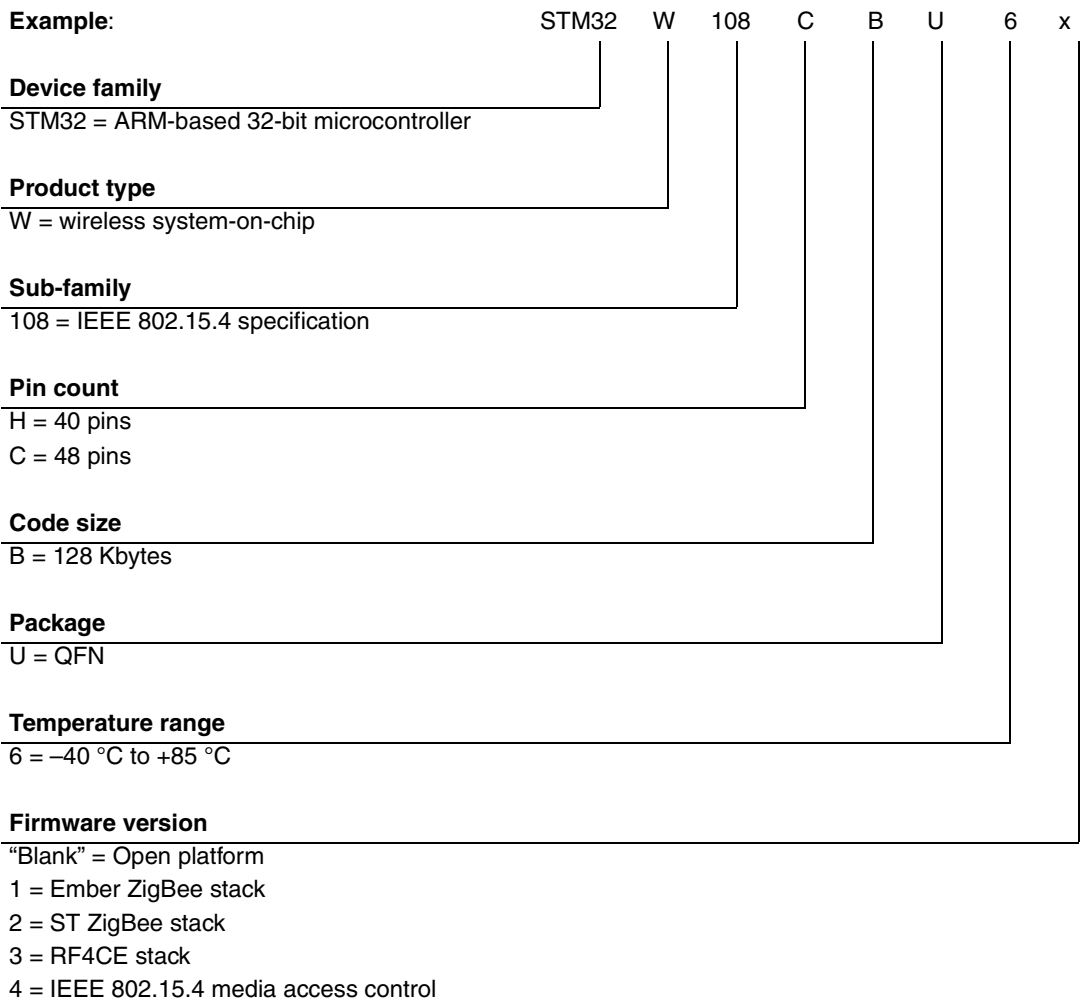


Table 15. QFN 40L 6x6mm package mechanical data

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	0.800	0.900	1.000	0.0315	0.0354	0.0394
A1		0.020	0.050		0.0008	0.0020
A2		0.720	1.070		0.0283	0.0421
A3		0.200			0.0079	
b	0.180	0.250	0.300	0.0071	0.0098	0.0118
D	5.900	6.000	6.100	0.2323	0.2362	0.2402
D2	4.500	4.550	4.700	0.1772	0.1791	0.1850
E		6.000			0.2362	
E2	4.500	4.550	4.700	0.1772	0.1791	0.1850
e		0.500			0.0197	
L	0.350	0.400	0.450	0.0138	0.0157	0.0177
ddd			0.080			0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

4 Ordering information scheme



For a list of available options (speed, package, etc.) or for further information on any aspect of this device, please contact your nearest ST sales office.

5 Revision history

Table 16. Document revision history

Date	Revision	Changes
20-Aug-2009	1	Initial release.

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